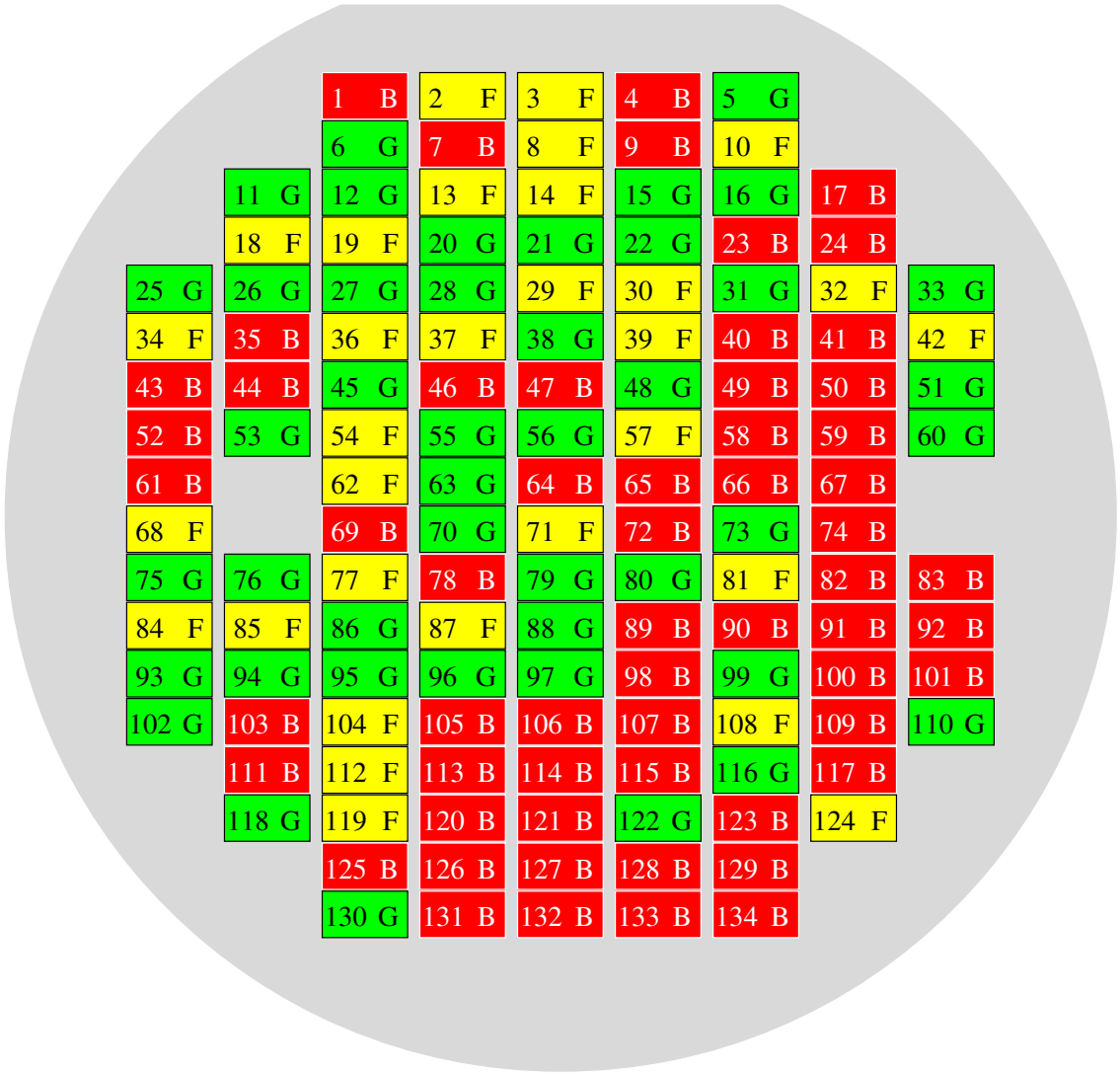
Die quality map for wafer 188 s/n: 21316-13-07

Date: 08/13/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged